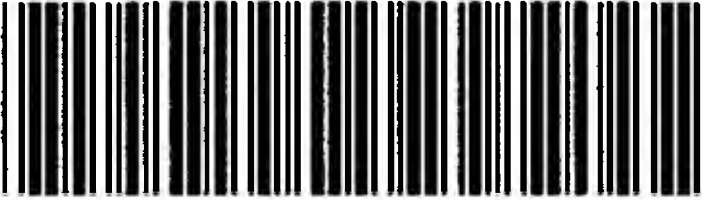


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/801,872	MEEK ET AL.	
	Examiner	Art Unit	
	Quynh H. Nguyen	2614	

